

1. CONTEXT

System / Assembly: _____

Config (Rev / Serial / Build): _____

Intended Environment / Use: _____

Consequence of Failure: ☐ Low ☐ Medium ☐ High

Baseline Evidence Exists (Prior Results / Known-Good Behavior): ☐ Yes ☐ No

2. WHAT CHANGED? (CHECK ALL THAT APPLY)

- | | |
|-------------------------------------------------------|------------------------------------------------------------------|
| <input type="checkbox"/> No Material Change | <input type="checkbox"/> Connector / Harness / Interface Change |
| <input type="checkbox"/> Obsolescence Substitution(s) | <input type="checkbox"/> Enclosure / Thermal / Mechanical Change |
| <input type="checkbox"/> PCB Layout / Stack-up Change | <input type="checkbox"/> Supplier / Process Change |
| <input type="checkbox"/> Firmware / Software Change | <input type="checkbox"/> Other: _____ |

3. CHOOSE THE APPROACH (FIRST PASS)

- ☐ **Acceptance-Focused:** Stable Design Intent + Strong Baseline
- ☐ **Targeted Qualification Style + Acceptance:** Most Legacy Changes
- ☐ **Full Qualification + Acceptance:** Major Change / New Environment / Weak Baseline

Reason (1-2 Sentences): _____

4. TEST LEVELS TO INCLUDE

- | | |
|--------------------------------------------------------|----------------------------------------------------------------------|
| <input type="checkbox"/> Bring-Up / Smoke | <input type="checkbox"/> Stress / Margin |
| <input type="checkbox"/> Functional | <input type="checkbox"/> Soak / Stability |
| <input type="checkbox"/> Interface (Timing / Protocol) | <input type="checkbox"/> Regression (if Firmware / Software Changed) |
| <input type="checkbox"/> Performance (Context Metrics) | <input type="checkbox"/> Other: _____ |

Defer to governing documents (contract/SOW/specs/acceptance criteria/config rules).

Right-size testing for legacy electronics changes (DoD / installed-base contexts). Ungated public resource.

5. CONDITIONS AND ASSUMPTIONS

Nominal Conditions Defined: ☐ Yes ☐ No

Worst-Case Conditions Selected: ☐ Voltage ☐ Load ☐ Temp ☐ Duty Cycle

Equivalence Assumptions Documents (if any): ☐ Yes ☐ No

6. PASS / FAIL, DISPOSITIONS, AND MINIMUM EVIDENCE

- ☐ Thresholds Written For Critical Tests
- ☐ Re-Test Rules Defined
- ☐ Deviations / Dispositions Recorded
- ☐ Evidence Pack Includes: Plan Version, Identifiers, Req-to-Test Map, Results, Deviations, Summary

7. QUESTIONS TO ASK ANY VENDOR / TEST GROUP

- What changed vs baseline, and what risks does that introduce?
- What tests directly address those risks (interfaces, timing, power, thermal)?
- What margin/stress checks were run beyond nominal?
- What evidence will be delivered (logs, screenshots, mapping, summary)?
- What is explicitly out of scope?

8. REVISION HISTORY

Revision	Date	Paragraph, Figure, Table Reference	A/M/D	Comments
0	1 December 2025			Initial Release

A = Added / M = Modified / D = Deleted

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